



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-1pq100m

Tables

Table 1	Product profile	1
Table 2	Plastic Device Resources	4
Table 3	Ceramic Device Resources	4
Table 4	Temperature Grade Offerings	5
Table 5	Speed Grade Offerings	5
Table 6	Voltage Support of MX Devices	13
Table 7	Fixed Capacitance Values for MX FPGAs (pF)	16
Table 8	Device Configuration Options for Probe Capability	17
Table 9	Test Access Port Descriptions	18
Table 10	Supported BST Public Instructions	18
Table 11	Boundary Scan Pin Configuration and Functionality	19
Table 12	Absolute Maximum Ratings for 40MX Devices*	20
Table 13	Absolute Maximum Ratings for 42MX Devices*	20
Table 14	Recommended Operating Conditions	21
Table 15	5V TTL Electrical Specifications	21
Table 16	Absolute Maximum Ratings for 40MX Devices*	22
Table 17	Absolute Maximum Ratings for 42MX Devices*	22
Table 18	Recommended Operating Conditions	22
Table 19	3.3V LVTTTL Electrical Specifications	23
Table 20	Absolute Maximum Ratings*	23
Table 21	Recommended Operating Conditions	24
Table 22	Mixed 5.0V/3.3V Electrical Specifications	25
Table 23	DC Specification (5.0 V PCI Signaling)	25
Table 24	AC Specifications (5.0V PCI Signaling)*	26
Table 25	DC Specification (3.3 V PCI Signaling)	27
Table 26	AC Specifications for (3.3 V PCI Signaling)*	27
Table 27	Package Thermal Characteristics	29
Table 28	42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CCA} = 5.0\text{ V}$)	38
Table 29	40MX Temperature and Voltage Derating Factors(Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CC} = 5.0\text{ V}$)	38
Table 30	42MX Temperature and Voltage Derating Factors(Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CCA} = 3.3\text{ V}$)	39
Table 31	40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CC} = 3.3\text{ V}$)	39
Table 32	Clock Specification for 33 MHz PCI	40
Table 33	Timing Parameters for 33 MHz PCI	40
Table 34	A40MX02 Timing Characteristics (Nominal 5.0 V Operation)	41
Table 35	A40MX02 Timing Characteristics (Nominal 3.3 V Operation)	43
Table 36	A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CC} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	46
Table 37	A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CC} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	49
Table 38	A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	52
Table 39	A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	56
Table 40	A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	60
Table 41	A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	64
Table 42	A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	67
Table 43	A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	71
Table 44	A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	75
Table 45	A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions,	

	VCCA = 3.0 V, T _J = 70°C)	79
Table 46	Configuration of Unused I/Os	84
Table 47	PL44	86
Table 48	PL68	88
Table 49	PL84	90
Table 50	PQ 100	93
Table 51	PQ144	97
Table 52	PQ160	102
Table 53	PQ208	107
Table 54	PQ240	113
Table 55	VQ80	120
Table 56	VQ100	123
Table 57	TQ176	126
Table 58	CQ208	132
Table 59	CQ256	138
Table 60	BG272	145
Table 61	PG132	153
Table 62	CQ172	158

2 40MX and 42MX FPGA Families

2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

2.2 Product Profile

The following table gives the features of the products.

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
Logic Modules						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
Clock-to-Out	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)						
	–	–	–	–	–	10
Dedicated Flip-Flops	–	–	348	624	954	1,230

2.6 Temperature Grade Offerings

Table 4 • Temperature Grade Offerings

Package	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
PLCC 44	C, I, M	C, I, M				
PLCC 68	C, I, A, M	C, I, M				
PLCC 84		C, I, A, M	C, I, A, M	C, I, M	C, I, M	
PQFP 100	C, I, A, M	C, I, A, M	C, I, A, M	C, I, M		
PQFP 144			C			
PQFP 160			C, I, A, M	C, I, M	C, I, A, M	
PQFP 208				C, I, A, M	C, I, A, M	C, I, A, M
PQFP 240						C, I, A, M
VQFP 80	C, I, A, M	C, I, A, M				
VQFP 100			C, I, A, M	C, I, A, M		
TQFP 176			C, I, A, M	C, I, A, M	C, I, A, M	
PBGA 272						C, I, M
CQFP 172				C, M, B		
CQFP 208						C, M, B
CQFP 256						C, M, B
CPGA 132			C, M, B			

Note: C = Commercial
 I = Industrial
 A = Automotive
 M = Military
 B = MIL-STD-883 Class B

2.7 Speed Grade Offerings

Table 5 • Speed Grade Offerings

	– F	Std	–1	–2	–3
C	P	P	P	P	P
I		P	P	P	P
A		P			
M		P	P		
B		P	P		

Note: See the 40MX and 42MX Automotive Family FPGAs datasheet for details on automotive-grade MX offerings.

Contact your local *Microsemi Sales representative* for device availability.

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 14 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCC (40MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCA (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V

Note: * Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

3.7.1 5 V TTL Electrical Specifications

The following tables show 5 V TTL electrical specifications.

Table 15 • 5V TTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					3.7		3.7		V
VOL ¹	IOL = 10 mA		0.5		0.5					V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX) ²		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL	VIN = 0.5 V		–10		–10		–10		–10	μA
IIH	VIN = 2.7 V		–10		–10		–10		–10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ³	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low power mode Standby Current	42MX devices only		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0	mA
IIO, I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3. All outputs unloaded. All inputs = VCC/VCCI or GND

3.8 3.3 V Operating Conditions

The following table shows 3.3 V operating conditions.

Table 16 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCC + 0.5	V
VO	Output Voltage	–0.5 to VCC + 0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 17 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCI+0.5	V
VO	Output Voltage	–0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 18 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCC (40MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCA (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCI (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

All the following tables show various specifications and operating conditions of 40MX and 42MX FPGAs.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{ja} (^\circ\text{C}/\text{W})} = \frac{150^\circ\text{C} - 70^\circ\text{C}}{(28^\circ\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

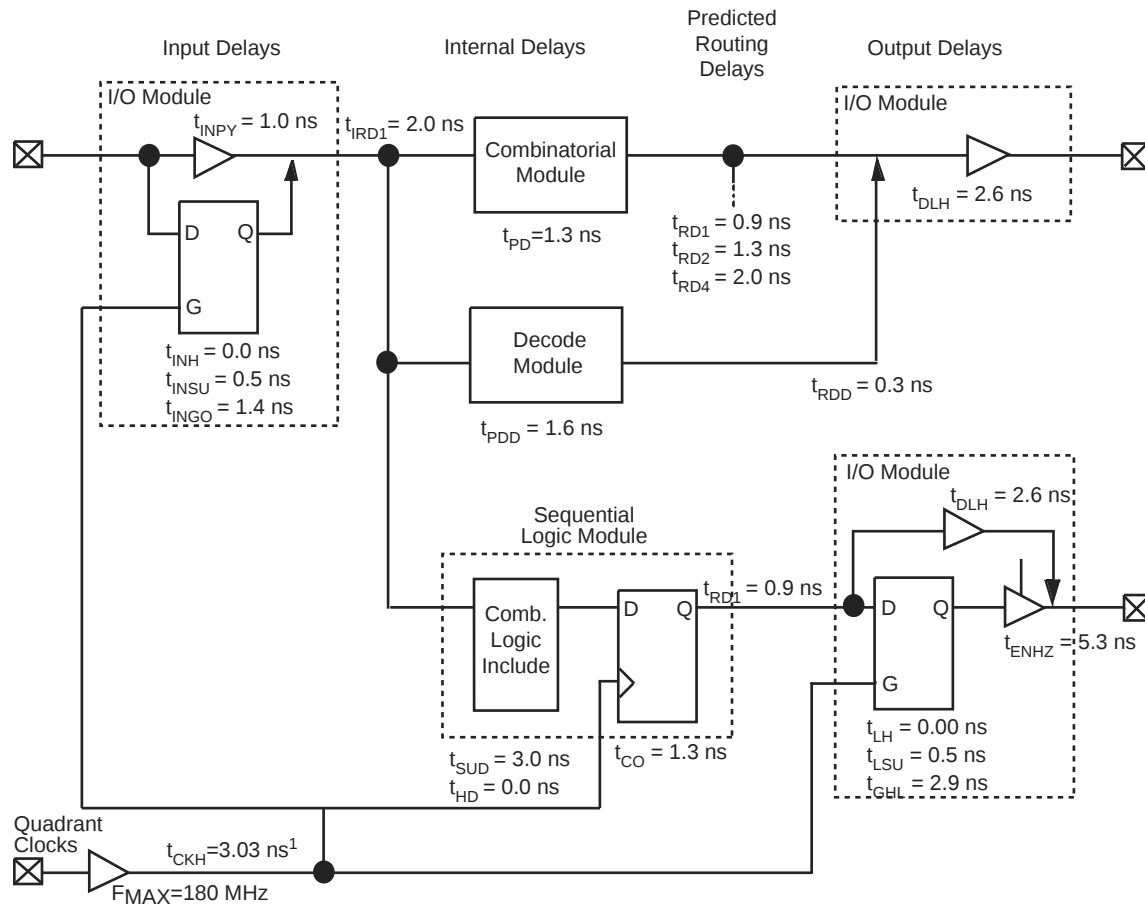
The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{jc} (^\circ\text{C}/\text{W})} = \frac{150^\circ\text{C} - 125^\circ\text{C}}{(6.3^\circ\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

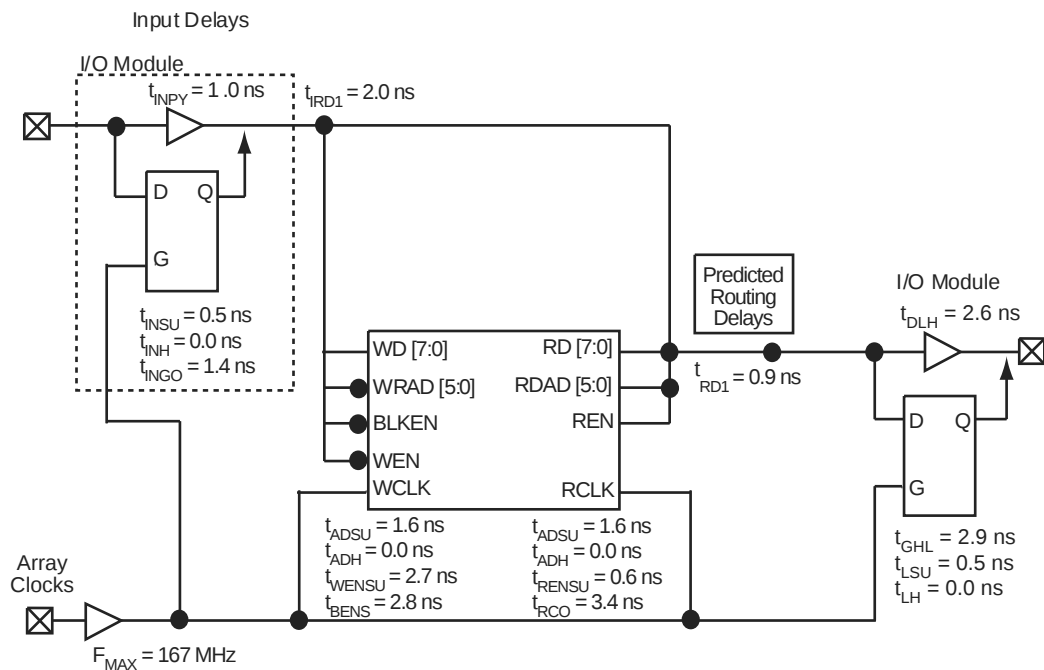
Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	$^\circ\text{C}/\text{W}$
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	$^\circ\text{C}/\text{W}$
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	$^\circ\text{C}/\text{W}$
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	$^\circ\text{C}/\text{W}$
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	$^\circ\text{C}/\text{W}$
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	$^\circ\text{C}/\text{W}$
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	$^\circ\text{C}/\text{W}$
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	$^\circ\text{C}/\text{W}$

Figure 19 • 42MX Timing Model (Logic Functions Using Quadrant Clocks)

Note: 1. Load-dependent

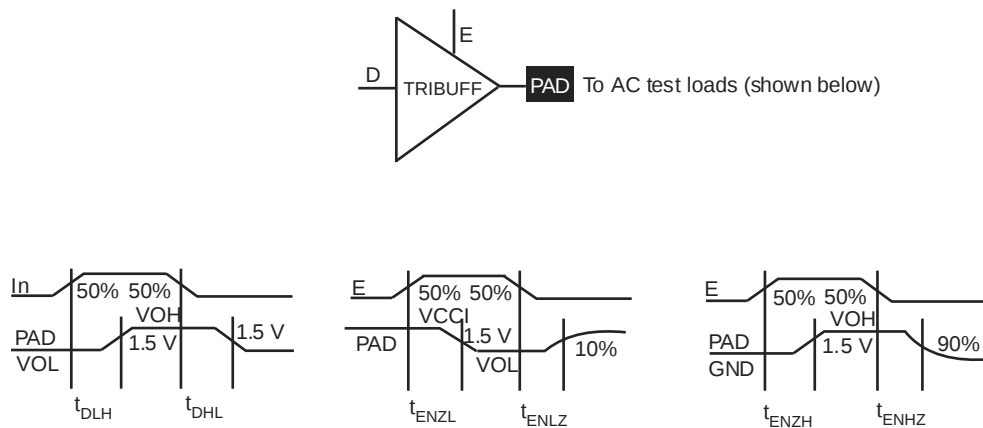
Note: 2. Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions

Figure 20 • 42MX Timing Model (SRAM Functions)

Note: Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

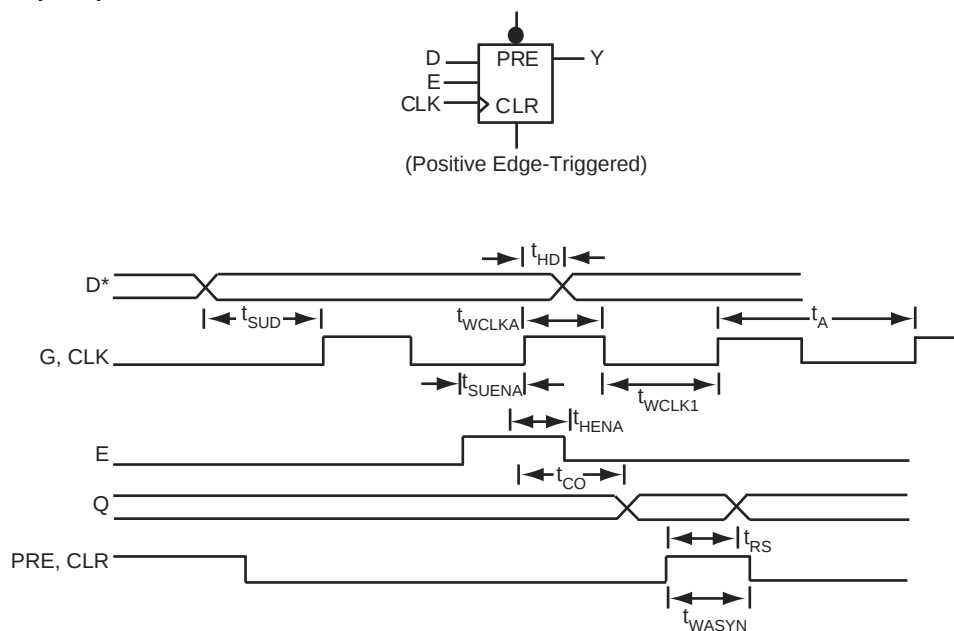
The following figures show parameter measurement details.

Figure 21 • Output Buffer Delays

3.10.2 Sequential Module Timing Characteristics

The following figure shows sequential module timing characteristics.

Figure 25 • Flip-Flops and Latches



Note: *D represents all data functions involving A, B, and S for multiplexed flip-flops.

3.10.3 Sequential Timing Characteristics

The following figures show sequential timing characteristics.

Figure 26 • Input Buffer Latches

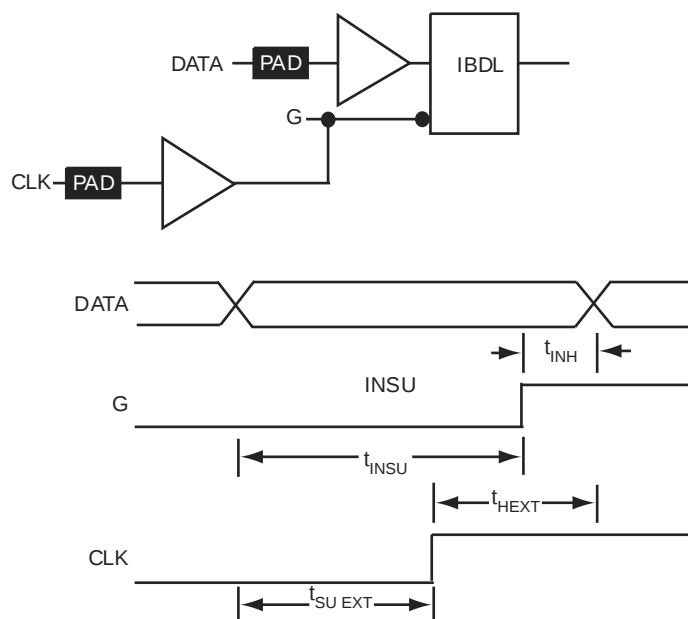


Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A	Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		268		244		224		195		117	MHz

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		2.5		2.7		3.1		3.6		5.1	ns
t _{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t _{ENZH}	Enable Pad Z to HIGH		2.6		2.9		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t _{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t _{GLH}	G-to-Pad HIGH		2.6		2.9		3.3		3.8		5.3	ns
t _{GHL}	G-to-Pad LOW		2.6		2.9		3.3		3.8		5.3	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵ (Continued)												
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.3		3.7		4.4		6.1	ns
t _{GHL}	G-to-Pad LOW		2.9		3.3		3.7		4.4		6.1	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.5		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		5.0		5.6		6.3		7.5		10.4	ns
t _{GHL}	G-to-Pad LOW		5.0		5.6		6.3		7.5		10.4	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.9		2.1		2.3		2.7		3.8	ns
t _{PDD}	Internal Decode Module Delay		2.2		2.5		2.8		3.3		4.7	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.7	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.0		2.3		2.7		3.7	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.5		2.8		3.4		4.7	ns
t _{RD4}	FO = 4 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ACO} Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d _{TLH} Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d _{THL} Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS Output Module Timing⁵											
t _{DLH} Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t _{DHL} Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH} Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t _{ENZL} Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t _{ENHZ} Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t _{ENLZ} Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t _{GLH} G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t _{GHL} G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t _{LSU} I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{LH} I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO} I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

3.12 Pin Descriptions

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/O Diagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output

Input, output, tristate or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/Os pins are configured by the Designer software as shown in Table 46, page 84.

Table 46 • Configuration of Unused I/Os

Device	Configuration
A40MX02, A40MX04	Pulled LOW
A42MX09, A42MX16	Pulled LOW
A42MX24, A42MX36	Tristated

In all cases, it is recommended to tie all unused MX I/O pins to LOW on the board. This applies to all dual-purpose pins when configured as I/Os as well.

LP, Low Power Mode

Controls the low power mode of all 42MX devices. The device is placed in the low power mode by connecting the LP pin to logic HIGH. In low power mode, all I/Os are tristated, all input buffers are turned OFF, and the core of the device is turned OFF. To exit the low power mode, the LP pin must be set LOW. The device enters the low power mode 800 ns after the LP pin is driven to a logic HIGH. It will resume normal operation in 200 μ s after the LP pin is driven to a logic LOW.

MODE, Mode

Controls the use of multifunction pins (DCLK, PRA, PRB, SDI, TDO). The MODE pin is held HIGH to provide verification capability. The MODE pin should be terminated to GND through a 10k Ω resistor so that the MODE pin can be pulled HIGH when required.

NC, No Connection

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

PRA, I/O

PRB, I/OProbe A/B

The Probe pin is used to output data from any user-defined design node within the device. Each diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. The Probe pin is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

QCLKA/B/C/D, I/O Quadrant Clock

Quadrant clock inputs for A42MX36 devices. When not used as a register control signal, these pins can function as user I/Os.

SDI, I/O Serial Data Input

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDO, I/O Serial Data Output

Serial data output for diagnostic probe and device programming. SDO is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW. SDO is available for 42MX devices only.

When Silicon Explorer II is being used, SDO will act as an output while the "checksum" command is run. It will return to user I/O when "checksum" is complete.

TCK, I/O Test Clock

Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
95	I/O	I/O	I/O
96	I/O	I/O	WD, I/O
97	I/O	I/O	I/O
98	VCCA	VCCA	VCCA
99	GND	GND	GND
100	NC	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	WD, I/O
107	I/O	I/O	WD, I/O
108	I/O	I/O	I/O
109	GND	GND	GND
110	NC	I/O	I/O
111	I/O	I/O	WD, I/O
112	I/O	I/O	WD, I/O
113	I/O	I/O	I/O
114	NC	VCCI	VCCI
115	I/O	I/O	WD, I/O
116	NC	I/O	WD, I/O
117	I/O	I/O	I/O
118	I/O	I/O	TDI, I/O
119	I/O	I/O	TMS, I/O
120	GND	GND	GND
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	NC	I/O	I/O
125	GND	GND	GND
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	NC	I/O	I/O
130	GND	GND	GND
131	I/O	I/O	I/O

Figure 47 • VQ100

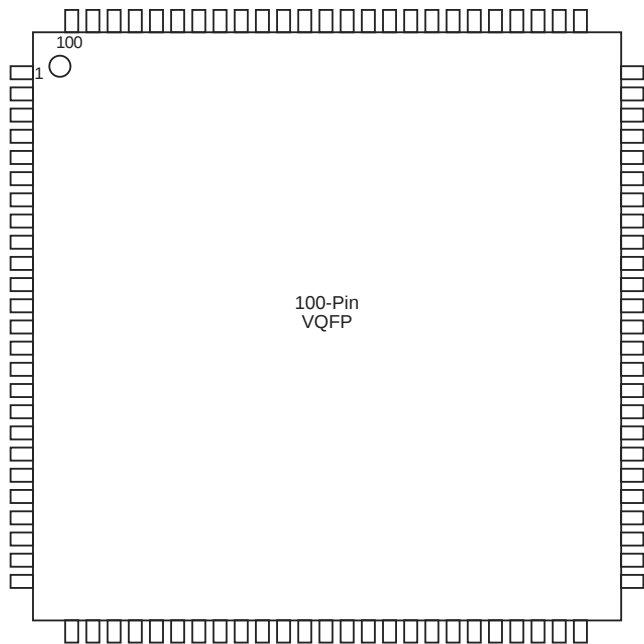


Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O
2	MODE	MODE
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	VCCA	NC
15	VCCI	VCCI
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	GND	GND

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	NC	VCCA	VCCA
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	GND	GND	GND
19	NC	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	NC	I/O	I/O
23	GND	GND	GND
24	NC	VCCI	VCCI
25	VCCA	VCCA	VCCA
26	NC	I/O	I/O
27	NC	I/O	I/O
28	VCCI	VCCA	VCCA
29	NC	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	NC	NC	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	NC	I/O	I/O
38	NC	NC	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	GND	GND	GND
46	I/O	I/O	TMS, I/O

Table 62 • CQ172

138	I/O
139	I/O
140	I/O
141	GND
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	PROBA
149	I/O
150	CLKA
151	VCC
152	GND
153	I/O
154	CLKB
155	I/O
156	PROBB
157	I/O
158	I/O
159	I/O
160	I/O
161	GND
162	I/O
163	I/O
164	I/O
165	I/O
166	VCCI
167	I/O
168	I/O
169	I/O
170	I/O
171	DCLK